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APPLICATION NO.	F	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/791,751		03/04/2004	Kazuo Tomita	402992	5267	
23548	7590 06/27/2005			EXAMINER		
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WASHINGT	ON, DC	20005-3960	2815			

DATE MAILED: 06/27/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

•		Applicat	ion No.	Applicant(s)					
		10/791,7	751	TOMITA ET AL.					
	Office Action Summary	Examine	er	Art Unit					
		Chris C.	Chu	2815					
Period fo	The MAILING DATE of this commu or Reply	nication appears on th	e cover sheet with the	correspondence add	ress				
THE I - Exter after - If the - If NO - Failur Any r	ORTENED STATUTORY PERIOD F MAILING DATE OF THIS COMMUN asions of time may be available under the provisions SIX (6) MONTHS from the mailing date of this come period for reply specified above is less than thirty (i period for reply is specified above, the maximum s re to reply within the set or extended period for reply peply received by the Office later than three months and patent term adjustment. See 37 CFR 1.704(b).	ICATION. s of 37 CFR 1.136(a). In no e munication. 30) days, a reply within the sta tatutory period will apply and v y will, by statute, cause the ap	. vent, however, may a reply be ti ututory minimum of thirty (30) da vill expire SIX (6) MONTHS fron plication to become ABANDONI	mely filed ys will be considered timely. the mailing date of this con ED (35 U.S.C. § 133).	nmunication.				
Status				•					
1)⊠	Responsive to communication(s) fil	ed on <i>08 April 2005</i> .		•					
•		2b) ☐ This action is	non-final.						
′—	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.								
Dispositi	on of Claims								
5)□ 6)⊠ 7)□	Claim(s) 1 - 12 is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration. Claim(s) is/are allowed. Claim(s) 1 - 12 is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and/or election requirement.								
Applicati	on Papers	i.							
10)⊠	The specification is objected to by the drawing(s) filed on <u>04 March 20</u> Applicant may not request that any objected from the oath or declaration is objected from the oath of the	004 is/are: a) ☐ acceection to the drawing(s) g the correction is requ	be held in abeyance. Se ired if the drawing(s) is o	ee 37 CFR 1.85(a). bjected to. See 37 CFI	R 1.121(d).				
Priority u	ınder 35 U.S.C. § 119								
12)⊠ a)l	Acknowledgment is made of a claim All b) Some * c) None of: 1. Certified copies of the priority 2. Certified copies of the priority 3. Copies of the certified copies application from the Internations See the attached detailed Office actions	y documents have be y documents have be s of the priority docun onal Bureau (PCT Ri	en received. en received in Applica nents have been receiv ule 17.2(a)).	tion No ved in this National S	Stage				
2) Notice 3) Inform	et(s) te of References Cited (PTO-892) te of Draftsperson's Patent Drawing Review (mation Disclosure Statement(s) (PTO-1449 o er No(s)/Mail Date <u>3/2/05</u> .		4) Interview Summar Paper No(s)/Mail [5) Notice of Informal 6) Other:	Date	-152)				

DETAILED ACTION

Response to Amendment

1. Applicant's amendment filed on April 8, 2005 has been received and entered in the case.

Drawings

2. The drawings are objected to under 37 CFR 1.83(a). The drawings must show every feature of the invention specified in the claims. Therefore, the following limitation in claim 9 "vias in the low-k dielectric film and in the cap film" must be shown or the feature(s) canceled from the claim(s). No new matter should be entered.

Corrected drawing sheets in compliance with 37 CFR 1.121(d) are required in reply to the Office action to avoid abandonment of the application. Any amended replacement drawing sheet should include all of the figures appearing on the immediate prior version of the sheet, even if only one figure is being amended. The figure or figure number of an amended drawing should not be labeled as "amended." If a drawing figure is to be canceled, the appropriate figure must be removed from the replacement sheet, and where necessary, the remaining figures must be renumbered and appropriate changes made to the brief description of the several views of the drawings for consistency. Additional replacement sheets may be necessary to show the renumbering of the remaining figures. Each drawing sheet submitted after the filing date of an application must be labeled in the top margin as either "Replacement Sheet" or "New Sheet" pursuant to 37 CFR 1.121(d). If the changes are not accepted by the examiner, the applicant will

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be notified and informed of any required corrective action in the next Office action. The objection to the drawings will not be held in abeyance.

Claim Rejections - 35 USC § 102

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3. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 4. Claims 1, 4 8, 11 and 12 are rejected under 35 U.S.C. 102(b) as being anticipated by Dirahoui et al. (U. S. Pat. No. 6,492,259).

Regarding claim 1, Dirahoui et al. discloses in e.g., Fig. 8 an interconnecting structure comprising:

- first wirings (12 and 14; column 4, lines 2 and 3) supported by a substrate (10; column 3, line 60);
- a low-k dielectric film (SOG 22; column 4, lines 47 50) on the first wirings, the
 low-k dielectric film having a dielectric constant not exceeding 3 (k is approximately
 2.7 see column 3, line 55 of Aoyama et al. U. S. Pat. No. 6,765,297);
- vias (26'; column 4, line 54) in a first portion of the low-k dielectric film and connected to the first wiring (12; see e.g., Fig. 8);
- second wirings (28; column 5, line 5 and column 2, lines 27) in a second portion, further from the substrate than the first portion, of the low-k dielectric film (22), on the vias (26'), and connected to the vias (26'; see e.g., Fig. 8); and

- dummy vias (24; column 4, lines 32 – 33) in the first portion of the low-k dielectric film (22) and on the periphery of an isolated via of the vias (26'; see e.g., Fig. 8).

Regarding claim 4, Dirahoui et al. discloses in e.g., Fig. 8 the dummy vias having a slit shape (see e.g., Fig. 8).

Regarding claims 5 and 7, Dirahoui et al. discloses in e.g., Fig. 8 the dummy vias (24) having an approximate dimension of a diameter that is similar as the diameter of non-dummy vias (26'). Thus, Dirahoui et al. discloses in e.g., Fig. 8 the dummy vias having a dimension 1 time of one of the dimensions of the vias.

Regarding claim 6, Dirahoui et al. discloses in e.g., Fig. 8 the vias (26') extending only in the first portion of the low-k dielectric film (22), and the dummy vias (24) extend through both the first and second portions of the low-k dielectric film (24) and do not contact the first wirings (12 or 14; see e.g., Fig. 8).

Regarding claims 8 and 12, Dirahoui et al. discloses in e.g., Fig. 8 all of the first wirings, the vias, the second wirings, and the dummy vias having a damascene structure (column 3, lines 36-39 and column 4, lines 29-32).

Regarding claim 11, Dirahoui et al. discloses in e.g., Fig. 8 an interconnecting structure comprising:

- first wirings (12 and 14) supported by a substrate (10);
- a low-k dielectric film (22) on the first wirings, the low-k dielectric film having a dielectric constant not exceeding 3;
- vias (26') in the low-k dielectric film and connected to the first wiring (see e.g. Fig.
 8);

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- second wirings (28) on the vias (26') and connected to the vias (26'; see e.g., Fig. 8), the second wiring having a surface coplanar with a surface of the low-k dielectric film (22; see e.g., Fig. 8); and

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- dummy vias (24) on the periphery of an isolated via of the vias (see e.g., Fig. 8).
- 5. Claims 9 and 10 are rejected under 35 U.S.C. 102(b) as being anticipated by Hagihara (JP 2001-168093 and U. S. Pat. No. 6,570,243: The Japanese publication is the basis for the rejection under 102(b). For the understanding, the U.S. reference will be cited as needed.).

Regarding claim 9, Hagihara discloses in e.g., Fig. 1(e) and Fig. 2 an interconnecting structure comprising:

- first wirings (the first wiring layer in the inner pattern region; column 6, lines 33 35) supported by a substrate (1);
- a low-k dielectric film (SOG film 5; column 6, line 42) on the first wirings, the low-k dielectric film having a dielectric constant not exceeding 3 (k is approximately 2.3 see column 1, lines 29 32 of Tsuji et al. U. S. Pat. No. 6,818,570);
- a cap film (6; column 6, line 43) on the low-dielectric film (5; see e.g., Fig. 1(e) and column 6, lines 50 52);
- vias (the via holes at elements forming region; column 6, lines 53 56) in the low-k
 dielectric film and in the cap film, the vias being connected to the first wiring;
- second wirings (the second wiring layer in the inner pattern region; column 7, lines 1
 4) on the vias and connected to the vias, the second wiring having a surface (at the

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bottom surface of the second wirings e.g., the bottom surface of the elements 8) coplanar with a surface of the cap film (top surface of the cap film 6); and

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- dummy vias (7 in Fig. 1(C); column 5, lines 55 – 57) on the periphery of an isolated via of the vias.

Regarding claim 10, the limitation "all of the first wirings, the vias, the second wirings, and the dummy vias have a damascene structure" is product by process claim limitation. Even though product-by-process claim is limited by and defined by the process, determination of patentability is based upon the product itself. The patentability of a product does not depend on its method of production. If the product in product-by-process claim is the same as or obvious from a product of the prior art, the claim is unpatentable even though the prior product is made by a different process. In re Thorpe, 227 USPQ 964, 966 (Fed. Cir. 1985) (citations omitted). A "product by process" claim is directed to the product per se, no matter how actually made. In re-Hirao, 190 USPO 15 at 17 (footnote 3). See also In re Brown, 173 USPO 685: In re Luck, 177 USPO 523; In re Fessmann, 180 USPO 324: In re Avery, 186 USPO 116; In re Wertheim, 191 USPO 90 (209 USPO 254 does not deal with this issue); and In re Marosi et al., 218 USPO 289 final product per se which must be determined in a "product by, all of" claim, and not the patentability of the process, and that an old or obvious product, whether claimed in "product by process" claims or not. Note that Applicant has the burden of proof in such cases, as the above caselaw makes clear.

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Claim Rejections - 35 USC § 103

6. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 7. Claim 2 is rejected under 35 U.S.C. 103(a) as being unpatentable over Dirahoui et al. in view of Lui et al. (U. S. Pat. No. 6,582,974).

While Dirahoui et al. discloses the use of the second wirings, Dirahoui et al. does not disclose a cap film on the low-k dielectric film. Lui et al. teaches in e.g., Fig. 6 a cap film (22a', 22b' and 22b'') on a low-k dielectric film (20a', 20b' and 20b''; column 7, lines 44 – 59), wherein second wiring (32a) is in the cap film (22a', 22b' and 22b'') and the low-k dielectric film (20a', 20b' and 20b''; see Fig. 6). It would have been obvious to one of ordinary skill in the art at the time when the invention was made to apply the cap film of Lui et al on the low-k dielectric film of Dirahoui et al. as taught by Lui et al. (1) to provide an etch stop and planarizing stop layer (column 8, lines 10 and 11) and (2) to prevent damage to the underlying metal lines (column 6, lines 4 – 6 of Yang et al.).

8. Claim 3 is rejected under 35 U.S.C. 103(a) as being unpatentable over Dirahoui et al. in view of Sugiyama et al. (U. S. Pat. No. 6,486,558).

Dirahoui et al. discloses in e.g., Fig. 8 further comprising:

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- first dummy wirings (since the wirings 18 are connected to the dummy vias 24, the wiring 18 read as first dummy wirings) on the periphery of the first wirings (12 and

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14; see e.g., Fig. 8); and

- second dummy wirings (the wirings on top of the elements 24 that are formed by a repeated process of the layer 22 on top of the layer 22; column 6, lines 39 and 40) on the periphery of the second wirings (28), wherein the dummy vias (24) are connected

to the first and second dummy wirings (column 6, lines 39 and 40).

However, Dirahoui et al. does not disclose one of the first and second dummy wirings connected to the dummy vias being connected to ground potential. Sugiyama et al. teaches in e.g., Fig. 7 one of a first (102 in the layer 88) and second (102 in the layer 90) dummy wirings connected to dummy vias (106) being connected to ground potential (column 7, lines 11 – 13). It would have been obvious to one of ordinary skill in the art at the time when the invention was made to modify Dirahoui et al. by applying the ground potential of Sugiyama et al. into the structure of Dirahoui et al. as taught by Sugiyama et al. The ordinary artisan would have been motivated to modify Dirahoui et al. in the manner described above for at least the purpose of electrically connecting the dummy wirings to the ground terminal of the substrate to stabilize capacitance (column 7, lines 65 – 67).

Response to Arguments

9. Applicant's arguments with respect to claim 1 have been considered but are moot in view of the new ground(s) of rejection.

Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, THIS ACTION IS MADE FINAL. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Chris C. Chu whose telephone number is 571-272-1724. The examiner can normally be reached on 11:30 - 8:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Tom Thomas can be reached on 571-272-1664. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent

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For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Chris C. Chu Examiner Art Unit 2815

c.c. Monday, June 20, 2005

GEORGE ECKERT
PRIMARY EXAMINER